

Search Notes

Application/Control No.

10/527,092

Examiner

/BINH K. TIEU/

Applicant(s)/Patent under
Reexamination

BEKANICH ET AL.

Art Unit

2614

SEARCHED

Class	Subclass	Date	Examiner
455	405-409	12/30/2007	BKT
↓	415	↓	↓
379	114.01		
↓	114.03		
↓	114.16		
↓	114.17		
↓	114.2		
↓	115.01		
↓	121.01-04		
↓	122		
↓	127.01		
↓	127.06		
↓	144.01		
↓	144.08	↓	↓

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR